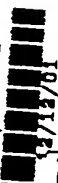


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U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM 10011802	FILING DATE 12/12/2001	CLASS 324	SUBCLASS	GAU 2858	EXAMINER
<b>**APPLICANTS:</b> Yan, Nien-Chang; Zhang, Yan; Chen, Chuan					
<b>**CONTINUING DATA VERIFIED:</b>					
<b>**FOREIGN APPLICATIONS VERIFIED:</b>					
PG-PUB. DO NOT PUBLISH <input checked="" type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> Yes <input checked="" type="checkbox"/> No		ATTORNEY DOCK NO.			
US USC 119 conditions met <input type="checkbox"/> Yes <input checked="" type="checkbox"/> No		AMD-G0420			
Continuation Acknowledged Examiner's notice <input type="checkbox"/> Yes <input checked="" type="checkbox"/> No					
TITLE: Method of determining gate oxide thickness of an operational MOSFET					

<b>NOTICE OF ALLOWANCE MAILED</b>		Assistant Examiner	<b>CLAIMS ALLOWED</b>	
			Total Claims	Print Claim for O.G.
<b>ISSUE FEE</b>		Primary Examiner	<b>DRAWING</b>	
Amount Due	Date Paid		Sheets Drawg.	Figs. Drawg.
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		<b>PREPARED FOR ISSUE</b>	Application Examiner	
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